

Field Effect Transistor - Dual, N & P-Channel, Enhancement Mode

NDC7001C

General Description

These dual N & P-Channel Enhancement Mode Field Effect Transistors are produced using **onsemi**'s proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. These device is particularly suited for low voltage, low current, switching, and power supply application.

Features

- Q1 0.51 A, 60 V
 - $R_{DS(ON)} = 2 \Omega @ V_{GS} = 10 V$ $R_{DS(ON)} = 4 \Omega @ V_{GS} = 4.5 V$
- Q2 -0.34 A, 60 V
 - $R_{DS(ON)} = 5 \Omega @ V_{GS} = -10 V$
 - $R_{DS(ON)} = 7.5 \Omega @ V_{GS} = -4.5 V$
- High Saturation Current
- High Density Cell Design for Low R_{DS(ON)}
- Proprietary SUPERSOT[™] -6 Package Design Using Copper Lead Frame for Superior Thermal and Electrical Capabilities
- This is a Pb-Free Device

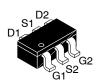
ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Symbol	Parameter			Q2	Unit
V _{DSS}	Drain-Source Voltage			-60	V
V _{GSS}	Gate-Source Voltage			±20	V
Ι _D	Drain Current	Continuous(Note 1a)	0.51	-0.34	Α
		- Pulsed	1.5	-1	Α
P_{D}	Power Dissipation for	(Note 1a)	0.96		W
	Single Operation	(Note 1b)	0.	9	W
		(Note 1c)	0.7		W
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
Reja	Thermal Resistance, Junction to Ambient (Note 1a)	130	°C/W
Rejc	Thermal Resistance, Junction to Case (Note 1)	60	°C/W



TSOT23 6-Lead SUPERSOT-6 CASE 419BL

MARKING DIAGRAM

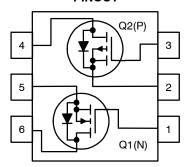


XXX = Specific Device Code

M = Date Code

■ = Pb-Free Package

PINOUT



ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Symbol	Parameter		Test Conditions		Min	Тур	Max	Unit
OFF CHARA	ACTERISTICS				-	-	-	-
BV _{DSS}	Drain-Source Breakdown Voltage)	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$ $V_{GS} = 0 \text{ V, I}_{D} = -250 \mu\text{A}$	Q1 Q2	60 –60	- -	- -	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient		I_D = 250 μA,Ref. to 25°C I_D = -250 μA,Ref. to 25°C	Q1 Q2	-	67 –57	- -	mV/°C
I _{DSS}	Zero Gate Voltage Drain Current		$V_{DS} = 48 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -48 \text{ V}, V_{GS} = 0 \text{ V}$	Q1 Q2		- -	1 -1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward		V _{GS} = 20 V, V _{DS} = 0 V	All	_	_	100	nA
I _{GSSR}	Gate-Body Leakage, Reverse		$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$	All	-	_	-100	nA
ON CHARA	CTERISTICS (Note 2)							
V _{GS(th)}	Gate Threshold Voltage	Q1	$V_{DS} = V_{GS}, I_D = 250 \mu A$		1	2.1	2.5	V
		Q2	$V_{DS} = V_{GS}, I_D = -250 \mu A$		-1	-1.9	-3.5	
$\Delta V_{GS(th)}$	Gate Threshold Voltage	Q1	I _D = 250 μA, Referenced to 25°C	;	-	-3.8	-	mV/°C
$\frac{\Delta T_{J}}{\Delta T_{J}}$	Temperature Coefficient	Q2	I _D = -250 μA, Ref. to 25°C		-	3.2	_	-
R _{DS(on)}	Static Drain–Source On–Resistance	Q1	В 11.7			1 2 1.7	2 4 3.5	Ω
		Q2	$V_{GS} = -10 \text{ V}, I_D = -0.34 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -0.25 \text{ A}$ $V_{GS} = -10 \text{ V}, I_D = -0.34 \text{ A}, T_J = -0.34 \text{ A}$		- - -	1.2 1.5 1.9	5 7.5 10	
I _{D(on)}	On–State Drain Current Q1 V _{GS} = 10 V, V _{DS} = 10 V		1.5	-	-	Α		
		Q2	$V_{GS} = -10 \text{ V}, V_{DS} = -10 \text{ V}$		-1	-	-	
9FS	Forward Transconductance	Q1	V _{DS} = 10 V, I _D = 0.51 A		-	380	-	mS
DYNAMIC (CHARACTERISTICS					•	•	
C _{iss}	C _{iss} Input Capacitance		For <i>Q1</i> : V _{DS} = 25 V, V _{GS} = 0 V f = 1.0 MHz		_	20	_	pF
					_	66	_	
C _{oss}	Output Capacitance	Q1	For <i>Q2</i> :		-	11	_	pF
		Q2	V _{DS} = -25 V, V _{GS} = 0 V f = 1.0 MHz		-	13	_	
C _{rss}	Reverse Transfer Capacitance	Q1	1 - 1.0 1/11/2		-	4.3	-	pF
		Q2			-	6	_	
R_{G}	Gate Resistance	Q1	V _{GS} = 15 mV, f = 1.0 MHz		-	11.2	-	Ω
		Q2			-	11.2	-	
WITCHING	CHARACTERISTICS (Note 2)							
t _{d(on)}	Turn-On Delay Time	Q1	For <i>Q1</i> :		-	2.8	5.6	ns
. ,		Q2	V_{DS} = 25 V, I_{DS} = 1 A V_{GS} = 10 V, R_{GEN} = 6 Ω		-	3.2	6.4	
t _r	Turn-On Rise Time	Q1	For <i>Q2</i> :		-	8	16	ns
		Q2	V_{DS} = -25 V, I_{DS} = -1 A V_{GS} = -10 V, R_{GEN} = 6 Ω		-	10	20	
t _{d(off)}	Turn-Off Delay Time	Q1	- GO - 10 1, 11GEN - 0 22		-	14	26	ns
. ,		Q2			-	8	16	
t _f	Turn-Off Fall Time	Q1			-	4	8	ns
		Q2			-	1	2	
Qg	Total Gate Charge	Q1	For <i>Q1</i> :		-	1.1	1.5	nC
-		Q2	V_{DS} = 25 V, I_{DS} = 0.51 A V_{GS} = 10 V, R_{GEN} = 6 Ω		-	1.6	2.2	
Q _{gs}	Gate-Source Charge	Q1	For <i>Q2</i> :		-	0.2	_	nC
-		Q2	V_{DS} = -25 V, I_{DS} = -0.35 A V_{GS} = -10 V, R_{GEN} = 6 Ω		-	0.3	_	
Q _{gd}	Gate-Drain Charge Q1		▼GS - 10 ▼,11GEN - 0 52		_	0.4	_	nC

ELECTRICAL CHARACTERISTICS ($T_A = 25$ °C unless otherwise noted) (continued)

Symbol	Parameter		Test Conditions		Min	Тур	Max	Unit	
PRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS									
I _S	Maximum Continuous Drain-Source Diode Forward Current		de Forward Current	Q1	-	-	0.51	Α	
				Q2	-	-	-0.34		
V_{SD}		Q1	V _{GS} = 0 V, I _S = 0.51 A (Note 2)		-	0.8	1.2	V	
	Voltage		V _{GS} = 0 V, I _S = -0.34 A (Note 2)		-	-0.8	-1.4		
t _{rr}	t _{rr} Diode Reverse Recovery Time		$I_F = 0.51 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		-	18	-	nS	
			$I_F = -0.34 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		-	16	_		
Q_{rr}	Diode Reverse Recovery				-	16	-	nC	
Charge		Q2	$I_F = -0.34 \text{ A}, d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		-	11	_		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{1.} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



a. 130°C/W when mounted on a 0.125 in² pad of 2 oz. copper.



b. 140°C/W when mounted on a .005 in² pad of 2 oz. copper.



Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0 %.

TYPICAL CHARACTERISTICS: N-CHANNEL

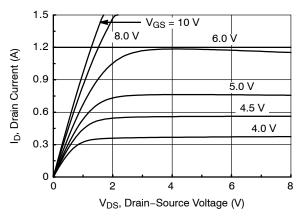


Figure 1. On-Region Characteristics

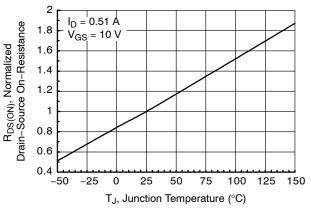


Figure 3. On–Resistance Variation with Temperature

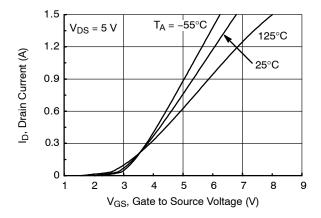


Figure 5. Transfer Characteristics

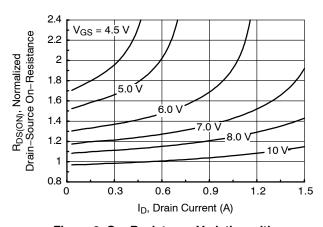


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

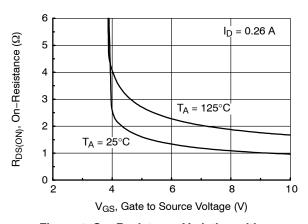


Figure 4. On–Resistance Variation with Gate–to–Source Voltage

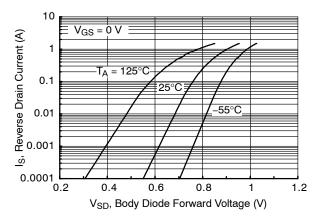


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

TYPICAL CHARACTERISTICS: N-CHANNEL (continued)

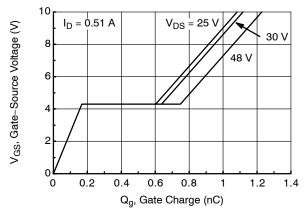


Figure 7. Gate Charge Characteristics

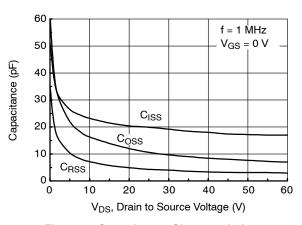


Figure 8. Capacitance Characteristics

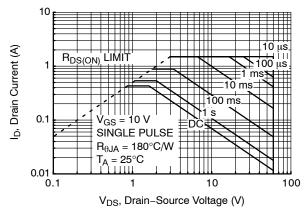


Figure 9. Maximum Safe Operating Area

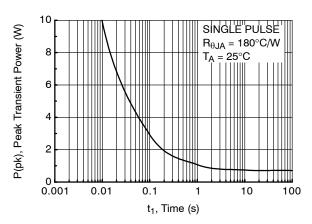


Figure 10. Single Pulse Maximum Power Dissipation

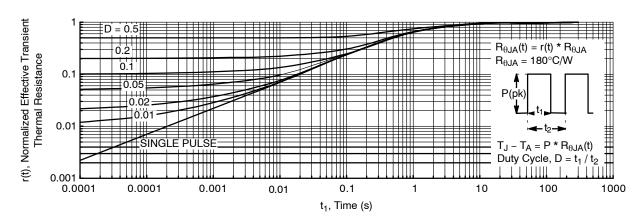


Figure 11. Transient Thermal Response Curve

(Note: Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.)

TYPICAL CHARACTERISTICS: P-CHANNEL

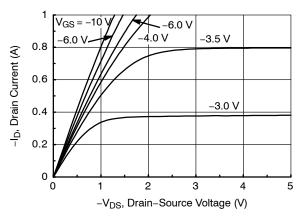


Figure 12. On-Region Characteristics

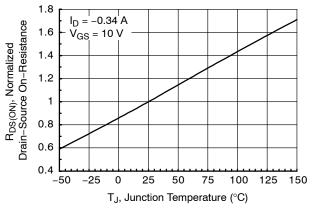


Figure 14. On–Resistance Variation with Temperature

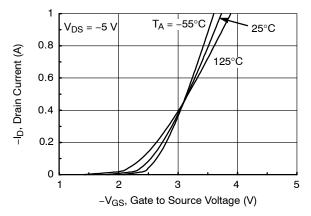


Figure 16. Transfer Characteristics

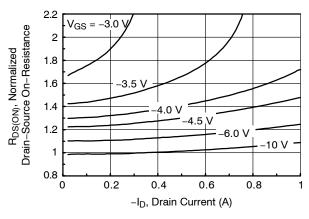


Figure 13. On-Resistance Variation with Drain Current and Gate Voltage

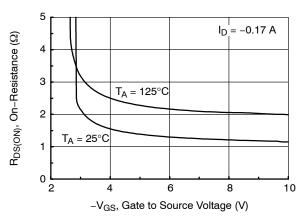


Figure 15. On-Resistance Variation with Gate-to-Source Voltage

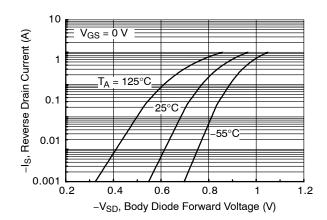


Figure 17. Body Diode Forward Voltage Variation with Current and Temperature

TYPICAL CHARACTERISTICS: P-CHANNEL (continued)

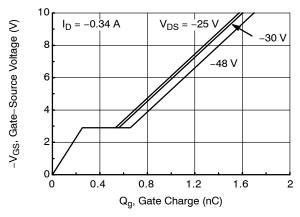


Figure 18. Gate Charge Characteristics

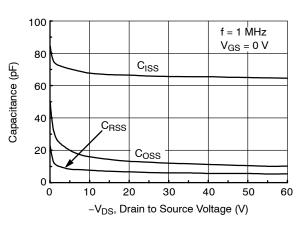


Figure 19. Capacitance Characteristics

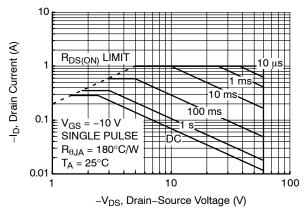


Figure 20. Maximum Safe Operating Area

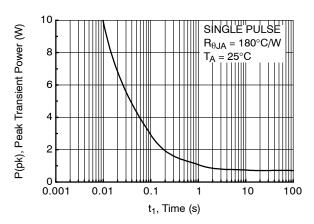


Figure 21. Single Pulse Maximum Power Dissipation

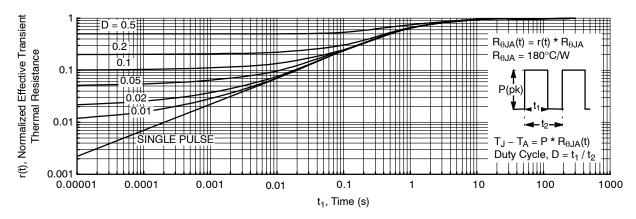


Figure 22. Transient Thermal Response Curve

(Note: Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.)

ORDERING INFORMATION

Device	Device Marking	Package Type	Reel Size	Tape Width	Shipping [†]
NDC7001C	.01	TSOT-23-6 (Pb-free)	7"	8 mm	3000 / Tape & Reel

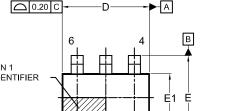
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

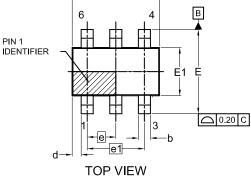
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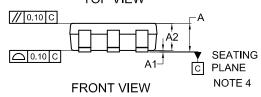


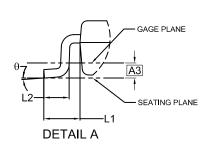
TSOT23 6-Lead CASE 419BL **ISSUE A**

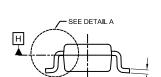
DATE 31 AUG 2020











SIDE VIEW 03/1414

SYMM
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0.95
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l 0.70 M I N

LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
 DIMENSIONS D AND E1 DO NOT INCLUDE MOLD FLASH,
 PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.25MM PER END. DIMENSIONS D AND E1 ARE DETERMINED AT DATUM H.
- 4. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

DIM	MILLIMETERS						
D ₁ ,v,	MIN.	NOM.	MAX.				
Α	0.90	1.00	1.10				
A1	0.00	0.05	0.10				
A2	0.70	0.85	1.00				
А3	0.25 BSC						
b	0.25	0.38	0.50				
С	0.10	0.18	0.26				
D	2.80	2.95	3.10				
d	0.30 REF						
Е	2.50	2.75	3.00				
E1	1.30	1.50	1.70				
е	(;					
e1	1.90 BSC						
L1	0.60 REF						
L2	0.20	0.40	0.60				
θ	0°	1	10°				

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code

= Date Code Μ

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON83292G	ON83292G Electronic versions are uncontrolled except when accessed directly from Printed versions are uncontrolled except when stamped "CONTROLLED		
DESCRIPTION:	TSOT23 6-Lead		PAGE 1 OF 1	

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